

MIL EMI and Transient Solutions

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Introduction

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28 Volt defense applications must meet a number of noise and power related standards such as MIL-STD-461, MIL-STD-704, and MIL-STD-1275. To complicate matters, there are a number of revisions to these standards, any of which may be enforced by the application. Additionally, within each standard are subsections that apply as dictated by the end installation. This Application Note will review these standards and offer means of achieving compliance when using Vicor's MIL-COTS V•I Chips (MP028F036M12AL and MV036FxxxMxxx series).

MIL-STD-461:

The latest revision of this standard is MIL-STD-461E. It is a comprehensive document addressing Conducted Emissions, Conducted Susceptibility, Radiated Emissions, and Radiated Susceptibility. Emission refers to the noise a device generates as it impacts the source to which it is connected. Susceptibility is the vulnerability of a system to incoming noise.

Table 1 shows the requirements for each substandard; and Table 2 illustrates the sections related to each of these and the applicability based upon installed platform. As can be observed from Table 2, not all sections are universally required. Hence, most power conversion suppliers focus on achieving compliance to the subset where all installations are affected and in particular to the conducted sections rather than the radiated. These standards are CE102, CS101, CS114, and CS116. Frequently, manufacturers will also reference CE101, as the switching frequency of most DC-DC converters are well beyond the frequency band of interest. Conducted emission and susceptibility requirements are quoted (and not radiated requirements) because radiated sections are significantly dependent upon the physical layout, external output circuitry and enclosure in which the power supply resides. A valid filter design and good PCB layout mean conducted requirements are easily met.

There is not much difference between revision E and the earlier revision D; in fact, of sections CE101, CE102, CS101, CS114, and CS116 only CS101 and CS114 are different. The extent of the differences are:

CS101 - No change up to 5 kHz; above 5 kHz:

461D: Required level drops 20 dB / decade to 50 kHz

461E: Required level drops 20 dB / decade to 150 kHz

CS114 - No change up to 30 MHz; above 30 MHz:

461D: Required level drops 10 dB / decade to 400 MHz 461E: Required level drops 10 dB / decade to 200 MHz







Requirement	Description
CE101	Conducted Emissions, Power Leads, 30 Hz to 10 kHz
CE102	Conducted Emissions, Power Leads, 10 kHz to 10 MHz
CE106	Conducted Emissions, Antenna Terminal, 10 kHz to 40 GHz
CS101	Conducted Susceptibility, Power Leads, 30 Hz to 150 kHz
CS103	Conducted Susceptibility, Antenna Port, Intermodulation, 15 kHz to 10 GHz
CS104	Conducted Susceptibility, Antenna Port, Rejection of Undesired Signals,
	30 Hz to 20 GHz
CS105	Conducted Susceptibility, Antenna Port, Cross-Modulation, 30 Hz to 20 GHz
CS109	Conducted Susceptibility, Structure Current, 60 Hz to 100 kHz
CS114	Conducted Susceptibility, Bulk Cable Injection, 10 kHz to 200 MHz
CS115	Conducted Susceptibility, Bulk Cable Injection, Impulse Excitation
CS116	Conducted Susceptibility, Damped Sinusoidal Transients,
	Cables and Power Leads, 10 kHz to 100 MHz
RE101	Radiated Emissions, Magnetic Field, 30 Hz to 100 kHz
RE102	Radiated Emissions, Electric Field, 10 kHz to 18 GHz
RE103	Radiated Emissions, Antenna Spurious and Harmonic Outputs, 10 kHz to 40 GHz
RS101	Radiated Susceptibility, Magnetic Field, 30 Hz to 100 kHz
RS103	Radiated Susceptibility, Electric Field, 2 MHz to 40 GHz
RS105	Radiated Susceptibility, Transient Electromagnetic Field

Table 1Summary of MIL-461-E
Requirements

Now we have introduced the standard, how do we gain compliance? What follows is a general guide for EMI filter design. We will focus on CE102 for our discussion.

Basics of EMI

EMI measurement are separated into two parts:

- Conducted
- Radiated

Conducted measurements are measurements of either voltages or currents flowing in the leads of the device under test (as dictated by the standard). Common mode conducted noise current is the unidirectional (in phase) component in both the positive and negative inputs to the module. This current circulates from the converter via the power input leads to the DC source and returns to the converter via the output lead connections. This represents a potentially large loop cross-sectional area that, if not effectively controlled, can generate magnetic fields. Common mode noise is a function of the dv/dt across the main switch in the converter and the effective input to output capacitance of the converter. Differential mode conducted noise current is the component of current, at the input power terminal, which is opposite in direction or phase with respect to each other.

For our purposes we will concentrate on MIL-STD-461, CE102 that is a voltage measurement into 50 ohms.

E-Field radiated emissions are due to conducted currents through a suitable antenna such as the power leads of the device under test. If we can greatly reduce the conducted emissions then we will reduce the radiated emissions as well. The enclosure of the device under test, lead geometry, and other devices running within the device under test will affect the emissions. Radiated emissions due to B-Fields are best addressed by shielding with a suitable material and proper layout.







Equipment and Subsystems Installed In, On, or Launched From the					Red	quir	em	ent	Ар	plic	abi	lity					
Following Platforms or Installations	<u> </u>						CS105	CS109	CS114	CS115	CS116	RE101	RE102	RE103	RS101	RS103	RS105
Surface Ships		Α	L	Α	S	S	S		Α	L	Α	Α	Α	L	Α	А	L
Submarines	А	Α	L	Α	S	S	S	L	Α	L	А	А	Α	L	Α	А	L
Aircraft, Army, Including Flight Line	Α	Α	L	Α	S	S	S		Α	Α	Α	Α	Α	L	Α	Α	L
Aircraft, Navy	L	Α	L	Α	S	S	S		Α	Α	Α	L	Α	L	L	А	L
Aircraft, Air Force		Α	L	Α	S	S	S		Α	Α	Α		Α	L		Α	
Space Systems, Including Launch Vehicles		Α	L	Α	S	S	S		Α	Α	Α		Α	L		Α	
Ground, Army		Α	L	Α	S	S	S		Α	Α	А		А	L	L	А	
Ground, Navy		А	L	Α	S	S	S		Α	Α	А		А	L	Α	Α	L
Ground, Air Force		Α	L	Α	S	S	S		Α	Α	А		А	L		А	

Table 2Section Requirement
Applicability

Legend:

- A Applicable
- L Limited as specified in the individual sections of this standard
- S Procuring activity must specify in procurement documentation

A defined test setup, known source impedance, and limits to which we can compare results are needed to get repeatable results. The standard test configuration is shown in Figure 1.

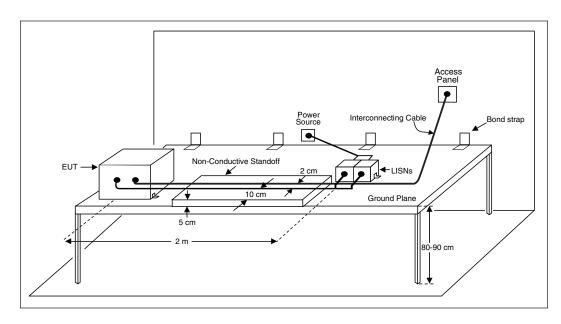


Figure 1 MIL-STD-461 Test Setup

The known impedance is realized with the use of Line Impedance Stabilization Networks (LISN) terminated into 50Ω (internal to the measurement device). One LISN per power lead is needed. This is illustrated in Figures 1 & 2.



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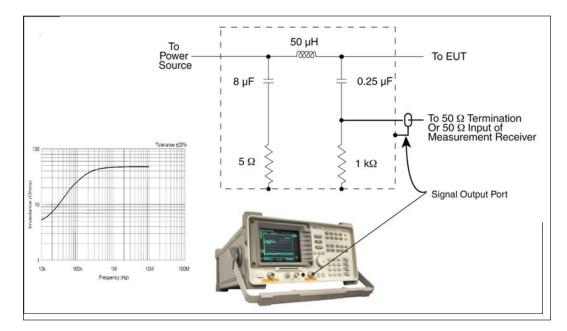


Figure 2 LISN Schematic and Impedance Graph

Figure 3 shows the spec limits. It is beneficial to translate the limits to millivolts in addition to the standard $dB\mu V$.

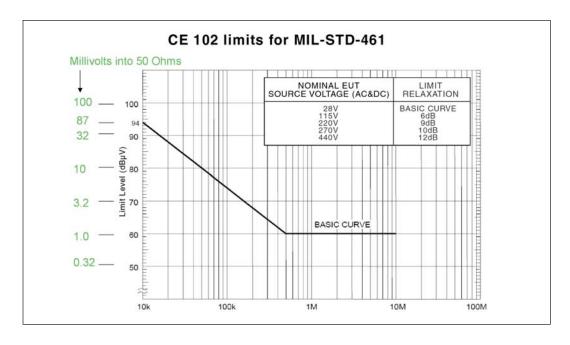


Figure 3

From the limits shown in Figure 3 for 28V systems, we can see that at 500kHz and above, the limit is 1Millivolt into 50 Ω . Given the limits, we will need to understand the source of the noise to determine the amount of attenuation required to stay below the limits. It is critical to understand the properties of the noise source in order to design a good filter.



Since in most cases the noise character of a device is unknown, the most effective solution is to have the device in hand prior to the development of a filter. The noise source can then be characterized through experimentation and, once characterized, a model can be generated. A good series of noise voltage measurements are:

- Input to ground open circuit.
- Input to ground 100-ohm shunt termination. (With DC blocking cap)
- Input to ground 10-ohm shunt termination. (With DC blocking cap)
- Input to ground 1-ohm shunt termination. (With DC blocking cap)
- Measurement of the short circuit common mode current input-output.

Let's assume the noise voltage measurements are:

Input to ground – open circuit.
 Input to ground – 100 ohm
 Input to ground – 10 ohm
 Input to ground – 10 ohm
 Input to ground – 1 ohm
 Short circuit (50nH) current input-output.

The equivalent circuit (model) would be most nearly a 10 V source as found from the open circuit test, with a series resistance of about 35 ohms. (10 V from the open circuit test and 0.28 A from the 1 ohm test)

Let's now investigate adding "Y" capacitance (from Line to Ground). This 4700 pF device has an impedance of ~13 Ω at 2.3 MHz (an assumed frequency of the ring wave measured in the 1 Ω termination test.) "Repeat" the measurement to observe the amplitude of the waveform. Let's also assume that the result of this measurement yields 1.3 V.

We now need to check our results:

A 10 V noise source with a series impedance of about 35 ohms is the model for the source. The "Y" capacitor has an impedance of 13 ohms at 2.7 MHz.

Solving for the voltage across the capacitor yields 2.7 V. The "measured" value across the 4700 pF capacitor is $1.3~{\rm V}$

Although this looks like a huge difference in percentage, we are only off -6.3 db from the calculations. The good news is the error is in the right direction.

So what do we know?

If we measure the conducted emissions using a LISN we would see a value of only slightly less than 1.3V. Our source impedance is still relatively low with respect to 50 ohms. i.e. 1.3 Vocv, lsc 0.29 A = 4.5 ohms.

Our target voltage measurement value is 1 mV, we only need 63 db of additional attenuation. Is it practical to continue to add shunt capacitance or impedances?

No, even if we could add as much shunt capacitance as we wanted the entire impedance, given an lsc current of 290 mA, would require the total shunt impedance <3.4 milliohms. This dictates that a practical filter must be constructed of a cascade of shunt and series devices forming an AC voltage divider. This is illustrated in Figure 4.







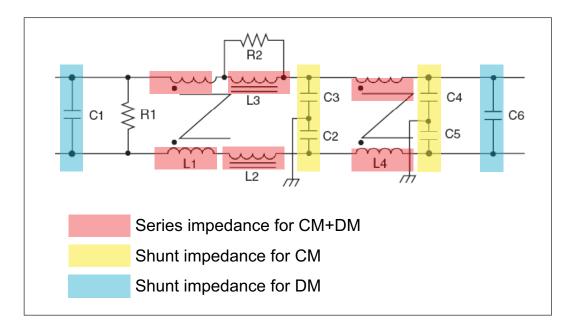


Figure 4

Multistage filter for

MIL-STD-461 compliance

For a good design we need to understand the impedance of every part and the potential interaction. It is good practice to keep the "Q" of the inductors and the ESR of the capacitors low for good attenuation without creating a resonance or as it is sometimes called "peaking". Layout of the filter is very important to avoid inadvertent parasitic coupling. For the example filter above, parasitic capacitance from input to output could easily be 1pF, which is about 60K ohms at 2.7 Mhz. If there were no shunt impedance looking back into the filter this would produce over 1mV at the LISN, putting us above the limit on its own.

The filter impedance (looking into the input) as well as additional "Y" capacitance either real or parasitic near C1 helps mitigate the effects of this parasitic. It is important to note that inductive coupling will have the same effect. Good layout practice is imperative so as to prevent input to output and stage to stage coupling.

Having a filter precede a power component has the added benefit of providing attenuation to transient fluctuations in the source voltage. Short duration, high dv/dt, events have little energy associated and the inductance and capacitance present in a filter is sometimes enough to integrate this energy by reducing the peak, and expanding the time as it appears at the output of the filter.

Unfortunately, the power supply to the application (as defined by the standard) can frequently exceed the capacity of the input filter to mitigate these power excursions; and so additional circuitry may be needed to transform them in such a way as to not affect the power device.

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Transient Immunity:

MIL-STD-704 and MIL-STD-1275 refer to aircraft and ground-based systems that describe the anticipated power quality of those systems, and the levels a device must meet or exceed in order to perform satisfactorily in the anticipated application. Other standards may be required but are not covered in this paper.

Tables 4-7 below give a summary of the most current revisions of 28 Vdc system requirements.

Specification	Test Description	Vstart Vdc	Time Sec	Vsurge Vdc	Tr ms	Duration msec	Tf ms	Vnom Vdc	Time sec	Remarks	Interval sec
RTCA DO-160E	Normal Surge	28	300	50	1	50	1	28	5	Repeat 3 times	5
Section 16 Power Input Airborne	Par. 16.6.1.4	28	300	12	1	30	1	28	5	Repeat 3 times	5
Equipment Category Z	Abnormal	28	300	80	ns	100	ns	28	ns	Repeat 3 times	10
category 2	Surge Par. 16.6.2.4	28	300	48	ns	1,000	ns	28	ns	Repeat 3 times	10
DEF STAN	Import Surge Generator	26.4	300	40	ns	50	50	26.4	1	Repeat 5 times	1
61-5, Part 6 28 Vdc	Plus Battery	26.4	300	20	ns	500	500	26.4	1	Repeat 5 times	1
Electrical Systems in	Import Surge	26.4	300	100	ns	50	150	26.4	1	Repeat 5 times	1
Military Vehicles	Generator Only	26.4	300	15.4	ns	500	150	26.4	1	Repeat 5 times	1
Mil-Std-1275D 28 Vdc Electrical	Normal Import Surge Gen + Batt	28	300	40	1	50	1	28	ns	Repeat 5 times	1
Systems In Mil Vehicles	Generator Only	28	300	100	1	50	1	28	ns	Repeat 5 times	1
	Voltage Surge	27.5	300	40	ns	30	ns	27.5	5		5
AIRBUS	Normal Trans.	27.5	300	17	ns	15	ns	27.5	5		5
ABD0100.1.8	Test 3.1	27.5	300	39	ns	50	ns	27.5	5	Repeat	5
Electrical	Test 3.2 Test 3.3	27.5	300	19.5	ns	30	ns	27.5	5	each =	5
Installation Conventional	Test 3.4	27.5	300	37	ns	100	ns	27.5	5	test 3	5
DC Network	1030 3.7	27.5	300	21	ns	50	ns	27.5	5	times -	5
Denetwork		27.5	300	35	ns	200	ns	27.5	5	- umes	5
		27.5	300	23.5	ns	100	ns	27.5	5		5

Table 3 28 V Transient Standard Summary

ns = not specified





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Duration Specification Vstart Time Vsurge Tr Vnom Time Remarks Interval Test Description Vdc Vdc ms Vdc Sec msec ms sec sec AIRBUS Voltage Surge ABD0100.1.8 **Abnorm Trans** Electrical Test 4.1 27.5 300 46 ns 100 ns 27.5 5 Repeat 5 Installation 300 38 1,000 5 Test 4.2 27.5 27.5 5 ns Conventional ns times DC Network 27.5 300 0 5,000 ns 27.5 5 5 ns Voltage Surge Norm Trans **AIRBUS** Test 2.1 27.5 300 36 100 27.5 5 ns ns ABD0100.1.8 Repeat 3 Test 2.2 27.5 300 35 200 27.5 5 5 ns ns Electrical Test 2.3 27.5 300 34 5 27.5 ns 300 5 Installation ns times Test 2.4 27.5 300 18.5 5,000 27.5 5 ns ns NBPT* Voltage Surge DC Network Abnormal * No Break Transients 5 27.5 300 36 1,000 27.5 5 Test 3.1 Repeat 3 Power ns ns 3,000 5,000 Transfer Test 3.2 300 33 ns ns 27.5 5 27.5 times Test 3.3 27.5 5 5 300 0 ns ns Normal Voltage Transients Overvoltage Mil-Std-704F AΑ 29 300 50 <1 12.5 <1 29 And ВВ 29 300 50 <1 12.5 70 29 Mil-HDBK-704 CC 29 300 40 <1 45 <1 29 Part 8 DD 29 300 40 45 37.5 29 <1 ΕE 29 300 50 <1 10 <1 29 Repeat 3x .0005 FF 22 22 50 300 12.5 22 <1 <1 GG 300 50 12.5 95 22 <1 НН 22 300 40 <1 22 <1 45

Table 4 28 V Transient Standard Summary

ns = not specified

Specification	Test Description	Vstart Vdc	Time Sec	Vsurge Vdc	Tr ms	Duration msec	Tf ms	Vnom Vdc	Time sec	Remarks	Interval sec
Mil-Std-704F And Mil-HDBK-704	Normal Voltage Transients Overvoltage										
Part 8 (cont.)	II	22	300	40	<1	45	62.5	22			
(cont.)	IJ	22	300	50	<1	10	<1	22		Repeat 3x	.0005
	Undervoltage										
	KK	29	300	18	<1	15	<1	29			
	LL	29	300	18	<1	15	234	29			
	MM	29	300	18	<1	10	<1	29		Repeat 3x	.0005
	NN	22	300	18	<1	15	<1	22			
	00	22	300	18	<1	15	85	22			
	PP	22	300	18	<1	10	<1	22		Repeat 3x	.0005
	Combined Transient										
	QQ	29 then	300	18 50	<1 <1	10 12.5	<1 70	29 29	<.001	Repeat 5 times	
	RR	22 then	300	18 50	<1 <1	10 12.5	<1 62.5	22 22	<.001	Repeat 5 times	
	Repetitive Normal Voltage										
	Transients	28.5	.0025	18	30	45 Vdc	2.5	28.5		Continous for 30 min.	.0005

Table 5 28V Transient Standard Summary



Specification Test Vstart Time Vsurge Tr Duration Tf Vnom Time Remarks Interval Description Vdc Sec Vdc msec ms Vdc sec Mil-Std-704F Abnormal Voltage And Mil-HDBK-704 Transients Overvoltage AAA Part 8 29 300 50 <1 50 <1 29 (cont.) 15 BBB29 300 50 <1 50 45 then 45 30 40 decreasing then 40 decreasing 60 35 35 decreasing 4,850 30 then then 30 decreasing 1,000 29 CCC .5 29 300 50 50 <1 29 Repeat 3x 22 22 DDD 300 50 50 <1 <1 EEE 22 300 50 <1 50 15 45 then 45 decreasing 30 40 then 40 35 60 decreasing 30 22 then 35 decreasing 4,850 30 8,000 then decreasing FFF 300 50 22 Repeat 3x .5 22 50 <1 <1 Undervoltage GGG 29 300 50 29 7 <1 <1 HHH 29 300 <1 50 15 12 then 30 increasing Na 17 22 17 60 then increasing Na then 22 4,850 increasing Na 28 then 28 1,000 increasing na 29 29 then

Table 6 28 V Transient Standard Summary

Specification	Test Description	Vstart Vdc	Time Sec	Vsurge Vdc	Tr ms	Duration msec	Tf ms	Vnom Vdc	Time sec	Remarks	Interval sec
Mil-Std-704F And Mil-HDBK-704 Part 8	Abnormal Voltage Transients Undervoltage										
(cont.)	III	29	300	7	<1	50	<1	29	<1	Repeat 3x	.5
(corre.)	111	22	300	7	<1	50	<1	22	<1		
	KKK	22	300	7	<1	50	15	12			
		then		12		increasing	30	17			
		then		17		increasing	60	22			
	LLL Combined	22	300	7	<1	50	<1	22		Repeat 3x	.5
	Transients MMM										
	IVIIVIIVI	29	300	7	<1	10	<1	50			
				50	<1	50	15	45			
		then		45		decreasing	30	40			
		then		40		decreasing	60	35			
		then		35		decreasing	4,850	30			
		then		30		decreasing	1	29			
		then		29							
	NNN	22	300	7	<1	10	<1	50			
				50	<1	50	15	45			
		then		45		decreasing	30	40			
		then		40		decreasing	60	35			
		then		35		decreasing	4,850	30			
		then		30		decreasing	8,000	22			
		then		22							

Table 7 28 V Transient Standard Summary





As with MIL-STD-461 there are earlier revisions of 704 and 1275 that may be required depending upon the installation. Be certain you know which one is being imposed because the limits can vary greatly.

MIL-STD-704F is relatively easy to meet. The tables 8-10 below summarize the important variations between the revisions of 704.

		28	3 Vdc Steady Sta	ate
		NORMAL (V)	ABNORMAL (V)	EMERGENCY (V)
MIL-STD-704A	Cat.A	25–28.5	23.5–30	17–24
	Cat.B	24–28.5	22.5–30	16–24
	Cat.C	23–28.5	21.5–30	15–24
MIL-STD-704C		22–29	20–31.5	16–30
MIL-STD-704D		22–29	20–31.5	16–29
MIL-STD-704E		22–29	20–31.5	18–29
MIL-STD-704F		22–29	20–31.5	16–29

Table 8 704 Revision Summary

The Surge differences are:

			28 Vdc Surges									
			Normal Operation Abnormal Operation									
		High Tra	ansients	Low Tra	nsients	High Tra	nsients	Low Tra	nsients			
		Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time			
MIL-STD-704A	Cat.A	70	20 mS	10	50 mS	80	50 mS	0	7 S			
	Cat.B	70	20 mS	8	50 mS	80	50 mS	0	7 S			
	Cat.C	70	20 mS	7	50 mS	80	50 mS	0	7 S			
MIL-STD-704C		50	12.5 mS	18	15 mS	50	45 mS	0	7 S			
MIL-STD-704D		50	12.5 mS	18	15 mS	50	45 mS	0	7 S			
MIL-STD-704E		50	12.5 mS	18	15 mS	50	50 mS	0	7 S			
MIL-STD-704F		50	12.5 mS	18	15 mS	50	50 mS	0	7 S			

Table 9 704 Revision Summary

And the Transient differences are:

			28 Vd	c Spikes						
		High Tr	ansients	Low Tra	ansients					
		Voltage (V)	Time	Voltage (V)	Time					
MIL-STD-704A	Cat. A	600	50 μS	-600	50 μS					
	Cat. B	600	50 μS	-600	50 μS					
	Cat. C	600	50 μS	-600	50 μS					
MIL-STD-704C			N	/A						
MIL-STD-704D			Spikes less th	nan 50 µS are						
			controlled by	y MIL-E-6051						
MIL-STD-704E		N/A								
MIL-STD-704F			N	/A						

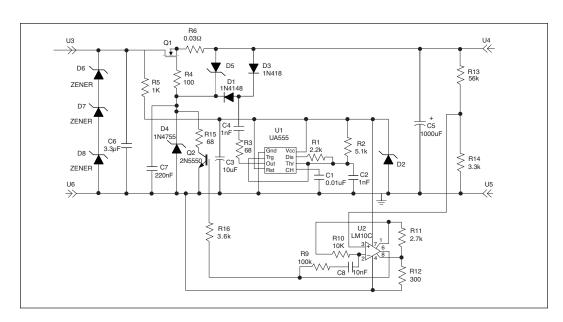
Table 10 704 Revision Summary



As can be seen from Tables 8-10, 704F is readily met if the power device has a normal input range of 16 -50Vdc - no special precautions or circuitry is needed. The Vicor M-PRM Model MP028F036M12AL has this input range, allowing for direct compliance to this standard.

If 704A is required to be met, the MP028F036M12AL needs additional protection - usually an input shunt Transorb to clamp the spike to a reasonable level, followed by an active clamp circuit using FETs to reduce the voltage to the output to the maximum level the DC device can tolerate. Figure 5 below illustrates the concept.

Figure 5 Example Clamp Circuit



Q1 is the main clamping element and must be sized appropriately to handle the power dissipation needed during the 80V (for 50ms) abnormal requirement. Obviously if the downstream device can handle a higher voltage, less power must be dissipated in Q1. D6-8 are in this example 33 V 600 W devices.

MIL-STD-1275D is a more severe requirement in that the Surge amplitude and duration is 100 Vdc for 50 ms. Tables 11-13 list the variations in revisions for MIL-STD-1275. As can be seen from these tables, with the exception of the 600V spikes from 704A, 1275D is more stringent. Therefore, if MIL-STD-1275D is met, 704F is met and because the Transorb handles the 600V spike, 704A is also met.

The circuit in Figure 5 could be built using discrete components, and an EMI filter could be designed using the methodology outlined earlier, but doing so requires iterations of build, test, evaluate, modify - dragging out the design phase of a project. To save time and ensure compliance, a ready-made product should be used, such as the Vicor M-FIAM7.



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Table 11 1275 Revision Summary

		28 Vdc Steady State	
	NORMAL (V)	GEN ONLY (V)	BATTERY ONLY (V)
MIL-STD-1275A (AT)	25–30	23–33	20–27
MIL-STD-1275B	25–30	23–33	20–27
MIL-STD-1275C	25–30	23–33	20–27
MIL-STD-1275D	25–30	23–33	

				28 Vdc	Surges				
		Fault Free	Operation		Single Fault Operation				
	High Tra	nsients	Low Tra	ansients	High Tra	nsients	Low Tra	ansients	
	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	
MIL-STD-1275A (AT)	40	50 mS	18.5	100 mS	100	50 mS	15	500 mS	
MIL-STD-1275B	40	50 mS	18.5	100 mS	100	50 mS	15	500 mS	
MIL-STD-1275C	40	50 mS	18	100 mS	100	50 mS	15	250 mS	
				28 Vdc	Surges				
		Normal Op	erating Mo	ode		Generator	Only Mod	е	
	High Tra	nsients	Low Tra	ow Transients High Transients Low Transie					
	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	
MIL-STD-1275D	40	50 mS	18	500 mS	100	50 mS	15	500 mS	

Table 12 1275 Revision Summary

				28 Vdc	Spikes						
		Fault Free Operation Single Fault Operation									
	High Tra	nsients	Low Tra	nsients	High Tra	nsients	Low Transients				
	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time			
MIL-STD-1275A (AT)	250	70 uS	-250	70 uS	250	70 uS	-250	70 uS			
MIL-STD-1275B	250	70 uS	-250	70 uS	250	70 uS	-250	70 uS			
MIL-STD-1275C	250	70 uS	-250	70 uS	250	70 uS	-250	70 uS			
				28 Vdc	Spikes						
		Normal Op	erating Mo	ode		Generator	Only Mod	е			
	High Tra	nsients	Low Tra	nsients	High Tra	nsients	Low Tra	nsients			
	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time	Voltage (V)	Time			
MIL-STD-1275D	250	70 uS	-250	70 uS	250	70 uS	-250	70 uS			

Table 13 1275 Revision Summary

Below in Figure 6 is a plot of the transient protection behavior of the M-FIAM7.

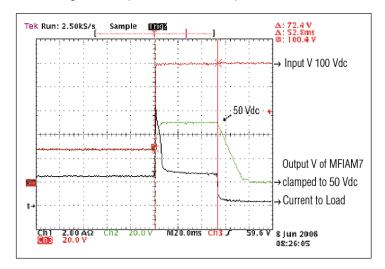


Figure 6





The pre-filter Conducted Emission (CE102) plot for a raw PRM/VTM pair is shown in Figure 7. Figure 8 shows the same plot after the addition of the M-FIAM7 with the measurement setup illustrated in Figure 9.

100 kMs 10 kMs 10 MMs 1

Figure 7

Note the bulk of the energy needing to be attenuated is at and above the switching frequency of the PRM/VTM pair

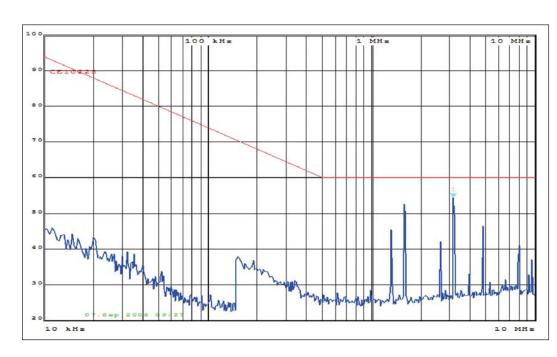


Figure 8CE102 Plot after the addition of M-FIAM7 and Y capacitance



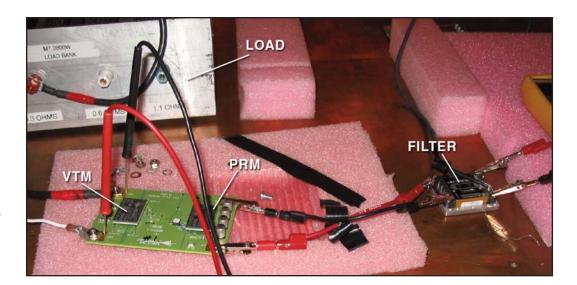


Figure 9 *Measurement setup*

Conclusion

Meeting the Compliance limits for EMI and Transient protection can be a daunting task. The steps involved in designing a filter from scratch, while doable, are tedious and time-consuming. Nevertheless this can be done if the steps outlined in this document are followed. A better method is to use a component such as the M-FIAM7 that has been designed by the manufacturer of the power component. Doing so assures compatibility with the device and a huge reduction in the design effort.

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